



Issue Date: February 29, 2012 Ref. Report No. ISL-12HE051CE

Product Name : Nuvo-1300af Series

Model(s) : Nuvo-1300af; Nuvo-1300af-620M; Nuvo-1300af-520M

Responsible Party : Neousys Technology Inc.

Address : 13F.-1, NO.1, BAOSHENG RD., YONGHE DIST., NEW TAIPEI CITY

23444, TAIWAN, R.O.C

#### We, International Standards Laboratory, hereby certify that:

The device bearing the trade name and model specified above has been shown to comply with the applicable technical standards as indicated in the measurement report and was tested in accordance with the measurement procedures specified in European Council Directive- EMC Directive 2004/108/EC. The device was passed the test performed according to:

#### **Standards:**

 $\epsilon$ 

EN 55022:2006 +A1:2007 / CISPR 22:2005 +A1:2005 / AS/NZS CISPR 22: 2009

EN 61000-3-2: 2006+A1:2009 +A2:2009 / IEC 61000-3-2: 2005+A1:2008 +A2:2009

EN 61000-3-3: 2008 and IEC 61000-3-3: 2008

EN 55024:1998+A1:2001+A2:2003 / CISPR 24:1997+A1:2001+A2:2002

EN 61000-4-2: 2009 and IEC 61000-4-2: 2008

EN 61000-4-3: 2006 + A1:2008and IEC 61000-4-3: 2006 + A1:2007

EN 61000-4-4: 2004 +A1:2010 and IEC 61000-4-4: 2004 +A1:2010

EN 61000-4-5: 2006 and IEC 61000-4-5: 2005

EN 61000-4-6: 2009 and IEC 61000-4-6: 2008

EN 61000-4-8: 2010 and IEC 61000-4-8: 2009

EN 61000-4-11: 2004 and IEC 61000-4-11: 2004

I attest to the accuracy of data and all measurements reported herein were performed by me or were made under my supervision and are correct to the best of my knowledge and belief. I assume full responsibility for the completeness of these measurements and vouch for the qualifications of all persons taking them.

**International Standards Laboratory** 

Jim Chu / Director

**⋈** Hsi-Chih LAB:

No. 65, Gu Dai Keng St., Hsichih District,

New Taipei City 22117, Taiwan

Tel: 886-2-2646-2550; Fax: 886-2-2646-4641



# CE MARK TECHNICAL FILE AS/NZS EMC CONSTRUCTION FILE

of

# **Product Name**

# Nuvo-1300af Series

Model

Nuvo-1300af; Nuvo-1300af-620M; Nuvo-1300af-520M

#### Contains:

- 1. Declaration of Conformity
- 2. EN55022/CISPR 22, AS/NZS CISPR 22 EMI test report
- 3. EN55024/CISPR 24, EN61000-3-2 / IEC 61000-3-2, and EN61000-3-3 / IEC 61000-3-3 test report
- 4. Block Diagram and Schematics
- 5. Users' manual

# **Declaration of Conformity**

Name of Responsible Party: Neousys Technology Inc.

Address of Responsible Party: 13F.-1, NO.1, BAOSHENG RD., YONGHE DIST.,

NEW TAIPEI CITY 23444, TAIWAN, R.O.C

Declares that product: Nuvo-1300af Series

Model: Nuvo-1300af;

Nuvo-1300af-620M; Nuvo-1300af-520M

Assembled by: Same as above Address: Same as above

Conforms to the EMC Directive 2004/108/EC as attested by conformity with the following harmonized standards:

EN 55022:2006 +A1:2007 / CISPR 22:2005 +A1:2005 / AS/NZS CISPR 22: 2009: Limits and methods of measurement of Radio Interference characteristics of Information Technology Equipment.

EN 55024:1998+A1:2001+A2:2003 / CISPR 24:1997+A1:2001+A2:2002: Information technology equipment-Immunity characteristics-Limits and methods of measurement.

Standard	Description	Results	Criteria
EN 61000-4-2:2009 IEC 61000-4-2:2008	Electrostatic Discharge	Pass	В
EN 61000-4-3:2006+A1:2008 IEC 61000-4-3:2006+A1:2007	Radio-Frequency, Electromagnetic Field	Pass	A
EN 61000-4-4: 2004 +A1:2010 IEC 61000-4-4: 2004 +A1:2010	Electrical Fast Transient/Burst	Pass	В
EN 61000-4-5: 2006 IEC 61000-4-5: 2005	Surge	Pass	В
EN 61000-4-6:2009 IEC 61000-4-6:2008	Conductive Disturbance	Pass	A
EN 61000-4-8:2010 IEC 61000-4-8:2009	Power Frequency Magnetic Field	Pass	A
EN 61000-4-11: 2004 IEC 61000-4-11: 2004	Voltage Dips / Short Interruption and Voltage Variation		
	>95% in 0.5 period	Pass	В
	30% in 25 period	Pass	С
	>95% in 250 period	Pass	С

<to be continued>

Standard	Description	Results
EN 61000-3-2: 2006 +A1:2009 +A2:2009 IEC 61000-3-2: 2005 +A1:2008 +A2:2009	Limits for harmonics current emissions	Pass
EN 61000-3-3: 2008 IEC 61000-3-3: 2008	Limits for voltage fluctuations and flicker in low-voltage supply systems.	Pass

We, Neousys Technology Inc., hereby declare that the equipment bearing the trade name and model number specified above was tested conforming to the applicable Rules under the most accurate measurement standards possible, and that all the necessary steps have been taken and are in force to assure that production units of the same equipment will continue to comply with the requirements.

-----

Neousys Technology Inc.

Date: February 29, 2012

# **Declaration of Conformity**

Name of Responsible Party: Neousys Technology Inc.

Address of Responsible Party: 13F.-1, NO.1, BAOSHENG RD., YONGHE DIST.,

NEW TAIPEI CITY 23444, TAIWAN, R.O.C

Declares that product: Nuvo-1300af Series

Model: Nuvo-1300af;

Nuvo-1300af-620M; Nuvo-1300af-520M

Assembled by: Same as above Address: Same as above

Conforms to the C-Tick Mark requirement as attested by conformity with the following standards:

EN 55022:2006 +A1:2007 / CISPR 22:2005 +A1:2005 / AS/NZS CISPR 22: 2009: Limits and methods of measurement of Radio Interference characteristics of Information Technology Equipment.

EN 55024:1998+A1:2001+A2:2003 / CISPR 24:1997+A1:2001+A2:2002: Information technology equipment-Immunity characteristics-Limits and methods of measurement.

Standard	Description	Results	Criteria
EN 61000-4-2:2009 IEC 61000-4-2:2008	Electrostatic Discharge	Pass	В
EN 61000-4-3:2006+A1:2008 IEC 61000-4-3:2006+A1:2007	Radio-Frequency, Electromagnetic Field	Pass	A
EN 61000-4-4: 2004 +A1:2010 IEC 61000-4-4: 2004 +A1:2010	Electrical Fast Transient/Burst	Pass	В
EN 61000-4-5: 2006 IEC 61000-4-5: 2005	Surge	Pass	В
EN 61000-4-6:2009 IEC 61000-4-6:2008	Conductive Disturbance	Pass	A
EN 61000-4-8:2010 IEC 61000-4-8:2009	Power Frequency Magnetic Field	Pass	A
EN 61000-4-11: 2004 IEC 61000-4-11: 2004	Voltage Dips / Short Interruption and Voltage Variation		
	>95% in 0.5 period	Pass	В
	30% in 25 period	Pass	С
	>95% in 250 period	Pass	С

<to be continued>

Standard	Description	Results
EN 61000-3-2: 2006 +A1:2009 +A2:2009 IEC 61000-3-2: 2005 +A1:2008 +A2:2009	Limits for harmonics current emissions	Pass
EN 61000-3-3: 2008 IEC 61000-3-3: 2008	Limits for voltage fluctuations and flicker in low-voltage supply systems.	Pass

We, Neousys Technology Inc., hereby declare that the equipment bearing the trade name and model number specified above was tested conforming to the applicable Rules under the most accurate measurement standards possible, and that all the necessary steps have been taken and are in force to assure that production units of the same equipment will continue to comply with the requirements.

-----

Neousys Technology Inc.

Date: February 29, 2012

# CE TEST REPORT

of EN55022 / CISPR 22 / AS/NZS CISPR 22 Class A EN55024 / CISPR 24 / IMMUNITY EN61000-3-2 / EN61000-3-3

Product: Nuvo-1300af Series

Model(s): Nuvo-1300af; Nuvo-1300af-620M;

Nuvo-1300af-520M

Applicant: Neousys Technology Inc.

Address: 13F.-1, NO.1, BAOSHENG RD., YONGHE

DIST., NEW TAIPEI CITY 23444, TAIWAN,

R.O.C

# Test Performed by:

# **International Standards Laboratory**

<Hsi-Chih LAB>

\*Site Registration No.

BSMI:SL2-IN-E-0037; SL2-R1/R2-E-0037; TAF: 1178;

IC: IC4067A-1; VCCI: R-341,C-354, T-1749, G-433; NEMKO: ELA

113A

\*Address:

No. 65, Gu Dai Keng St.

Hsichih District, New Taipei City 22117, Taiwan \*Tel: 886-2-2646-2550; Fax: 886-2-2646-4641

Report No.: **ISL-12HE051CE**Issue Date: **February 29, 2012** 

This report totally contains 52 pages including this cover page and contents page.

Test results given in this report apply only to the specific sample(s) tested and are traceable to national or international standard through calibration of the equipment and evaluating measurement uncertainty herein.

This report MUST not be used to claim product endorsement by TAF, NEMKO or any agency of the Government.

This test report shall not be reproduced except in full, without the written approval of International Standards Laboratory.





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# 1. General

#### 1.1 Certification of Accuracy of Test Data

Please refer to 1.2 **Standards:** 

Nuvo-1300af Series **Equipment Tested:** 

**Model:** Nuvo-1300af; Nuvo-1300af-620M; Nuvo-1300af-520M

**Applicant:** Neousys Technology Inc.

**Sample received Date:** February 13, 2012

EMI:refer to the date of test data **Final test Date:** 

EMS: February 29, 2012

**Test Site: International Standards Laboratory** 

OATS 01; Chamber 01; Conduction 01; Immunity01

**Test Distance:** 10M; 3M (above1GHz) (EMI test)

refer to each site test data **Temperature:** 

**Humidity:** refer to each site test data

**Input power:** Conduction input power: AC 230 V / 50 Hz

Radiation input power: AC 230 V / 50 Hz

Immunity input power: AC 230 V / 50 Hz

**Report Number: ISL-12HE051CE** 

**Test Result: PASS** 

Midori Su **Report Engineer:** 

EDDIE CHUNG **Test Engineer:** 

**Approved By:** 

Eddy Hisung



#### 1.2 Test Standards

The tests which this report describes were conducted by an independent electromagnetic compatibility consultant, International Standards Laboratory in accordance with the following

EN 55022:2006 + A1:2007 / CISPR 22:2005 + A1:2005 / AS/NZS CISPR 22:2009: Class A: Limits and methods of measurement of Radio Interference characteristics of Information Technology Equipment.

EN 55024:1998+A1:2001+A2:2003 / CISPR 24:1997+A1:2001+A2:2002: Information technology equipment-Immunity characteristics-Limits and methods of measurement.

Standard	Description	Results	Criteria
EN 61000-4-2:2009 IEC 61000-4-2:2008	Electrostatic Discharge	Pass	В
EN 61000-4-3:2006+A1:2008 IEC 61000-4-3:2006+A1:2007	Radio-Frequency, Electromagnetic Field	Pass	A
EN 61000-4-4: 2004 +A1:2010 IEC 61000-4-4: 2004 +A1:2010	Electrical Fast Transient/Burst	Pass	В
EN 61000-4-5: 2006 IEC 61000-4-5: 2005	Surge	Pass	В
EN 61000-4-6:2009 IEC 61000-4-6:2008	Conductive Disturbance	Pass	A
EN 61000-4-8:2010 IEC 61000-4-8:2009	Power Frequency Magnetic Field	Pass	A
EN 61000-4-11: 2004 IEC 61000-4-11: 2004	Voltage Dips / Short Interruption and Voltage Variation		
	>95% in 0.5 period	Pass	В
	30% in 25 period	Pass	С
	>95% in 250 period	Pass	С

Standard	Description	Results
EN 61000-3-2: 2006 +A1:2009 +A2:2009 IEC 61000-3-2: 2005 +A1:2008 +A2:2009	Limits for harmonics current emissions	Pass
EN 61000-3-3: 2008 IEC 61000-3-3: 2008	Limits for voltage fluctuations and flicker in low-voltage supply systems.	Pass



#### 1.3 Description of EUT

**EUT** 

Description: Nuvo-1300af Series Condition: Pre-Production

Model: Nuvo-1300af; Nuvo-1300af-620M; Nuvo-1300af-520M

Serial Number: N/A

Power Supply Type: Meanwell (Model: GS160A20)

AC Input: 100-240V, 2.0A, 50/60Hz

DC Output: +20V/8A (with core), 160W MAX.

CPU: Intel® Core<sup>TM</sup> i7-620M Processor 2.6GHz

DIMM Memory: DSL 4GB DDR3-1333MHz \*2

Solid State Disk: InnoDisk (Model: FiD 2.5" SATA 10000 16GB WT.) 16GB

Seagate(Model: ST980817SM) 80GB

Power Switch Button: one CFast Socket: one Hard Disk Socket: two

VGA Port (Onboard VGA): one (15-pins)

DVI Port (Onboard DVI): one

RJ45 Connector: one (8-pins) (10/100/1000Mbps)

RJ45 Connector(PoE): four (8-pins) (100Mbps)

PS/2 Mouse Port: one (6-pins)
PS/2 Keyboard Port: one (6-pins)
USB 2.0 Port: eight (4-pins)

Line-out Port: one Microphone Port: one

Isolated DIO Connector: one (25-pins)
COM Port: four (9-pins)
E-Serial ATA Port: one (7-pins)

DC power Port: two

Highest frequency of the internal sources of the EUT is 2.6GHz

**Test Configuration:** 

Model: Nuvo-1300af

CPU 2: Intel® Core<sup>TM</sup> i7-620M Processor 2.6GHz

Memory: DSL 4GB DDR3-1333MHz \*2

Display Type: D-SUB + DVI

SPS: Meanwell (Model: GS160A20)

Solid State Disk: InnoDisk (Model: FiD 2.5" SATA 10000 16GB WT.) 16GB

Seagate (Model: ST980817SM)80GB

**Report Number: ISL-12HE051CE** 

PoE-LAN Speed: 100Mbps\*4 LAN Speed: 1000Mbps\*1



**Report Number: ISL-12HE051CE** 

# **Model Difference List:**

Only CPU Different.

# **EMI Noise Source**

Crystal: 25MHz (X1), 25MHz (X2), 32.768MHz (X3), 25MHz (X4), 25MHz (X5), 25MHz (X6), 25MHz (X7), 25MHz (X8), 25MHz (X9)

# **EMI Solution:**

1. Added one Core on Power Supply Type cable • (Reference EUT photo 6)



# 1.4 Description of Support Equipment

Unit	Model	Brand	Power Cord	FCC ID
	Serial No.			
Notebook	Latitude D400	DELL	Non-shielded,	FCC DOC
Personal	S/N: N/A		Detachable	
Computer				
24" LCD	2408WFP	DELL	Non-Shielded,	FCC DOC
Monitor	S/N: N/A		Detachable	
24" LCD	U2410	DELL	Non-Shielded,	FCC DOC
Monitor	S/N: N/A		Detachable	
External	OT-201	A-TEC	N/A	FCC DOC
HDD	S/N: N/A			
Enclosure*8				
E-SATA			Non abialded	
External	NST-200SU-BK	NexStar	Non-shielded, Detachable	FCC DOC
Hard Disk			Detachable	
Keyboard	SK-8115, S/N:	DELL	N/A	FCC DOC
	MY-05N456-3884			
	3-2BK-3315			
Mouse	MO71KC	DELL	N/A	FCC DOC
	S/N: 511092011			
Modem*4	DM1414	Aceex	Non-shielded,	IFAXDM1414
	S/N: 0301000557		Without Grounding	
	0301000558		Pin	
	0301000559			
	0301000560			
Headphone	00010000		N 1.1.1.1	
&	CD-85	JS	Non-shielded, Detachable	FCC DOC
Microphone			Detachable	
Rack			D-Link	
mountable	DGS-1008D	D-Link	(Model:AF-1205-B)	FCC DOC
Switch			(Model.Al'-1203-b)	
Camera1	PoE IP Network	LEVEL	N/A	FCC DOC
Calliciai	Camera	ONE	IN/A	ree boe
Camera2	a12105L81009V0	IP	N/A	FCC DOC
Calliciaz	a12103L61009 v 0	CAMERA	IN/A	ree boe
	acA640-100gc			
Comono 2	ID:0000104844-0	DACLED	NT/A	NT/A
Camera3	3F	BASLER	N/A	N/A
	S/N:21011292			
D-E AD 0	VigorAP800			
PoE AP &	S/N:11800192125	DrayTek	N/A	VGYVFLY200
Switch Hub	5	_		



### 1.5 Software for Controlling Support Unit

Test programs exercising various part of EUT were used. The programs were executed as follows:

- A. Read and write to the disk drives.
- B. Read and write External HDD Enclosure from USB port.
- C. Read and write E-SATA Hard from E-SATA port.
- D. Read and write to the CF card.
- E. Read and write print port through DIO\_test tool.
- F. Send video signal to POE1 port of EUT through Camera1.
- G. Send video signal to POE3 port of EUT through Camera2.
- H. Send video signal to POE4 port of EUT through Camera3.
- I. Send signal to PoE AP & Switch Hub through POE2 port of EUT.
- J. Send audio signal to the Headset through line out port.
- K. Send H pattern to the serial port device (Modem).
- L. Send H pattern to the video port device (Monitor).
- M. Receive and transmit package of EUT to the Rack mountable Switch HUB through LAN port.

- N. Used Tfgen.exe to Send signal to EUT RJ45 port through PC RJ45 Port.
- O. Repeat the above steps.

	Filename	<b>Issued Date</b>
External Hard Disk	BurnIn Test.exe	11/20/2000
E-SATA	BurnIn Test.exe	11/20/2000
Modem	BurnIn Test.exe	11/20/2000
Monitor	BurnIn Test.exe	11/20/2000
EUT Hard Disk	BurnIn Test.exe	11/20/2000
CF Card	BurnIn Test.exe	11/20/2000
ATA Microphone and HeadSet	Windows Media player.exe	02/18/2006
Rack mountable Switch	ping.exe	05/05/1999
RJ45	Tfgen.exe	05/22/2001



# 1.6 I/O Cable Condition of EUT and Support Units

Description	Path	Cable Length	Cable Type	Connector Type
AC Power Cord	110V (~240V) to EUT SPS	1.8M	Non-shielded, Detachable	Plastic Head
USB Data Cable*8	External HDD Enclosure USB Port to EUT USB Port	0.98M	Non-shielded, Detachable (With Core)	Metal Head
E-SATA Data Cable	External Hard disk E-SATA Port to EUT E-SATA Port	1.0M	Shielded, Detachable	Metal Head
LAN Data Cable	Notebook LAN Port to Switch HUB LAN Port	2.0M	Non-shielded, Detachable	RJ-45, with Plastic Head
PoE Data Cable	EUT PoE Port to Camera1 PoE Port	10M	Non-shielded, Detachable	RJ-45, with Plastic Head
PoE Data Cable	EUT PoE Port to PoE AP & Switch Hub PoE Port	10M	Non-shielded, Detachable	RJ-45, with Plastic Head
PoE Data Cable	EUT PoE Port to Camera2 PoE Port	10M	Non-shielded, Detachable	RJ-45, with Plastic Head
PoE Data Cable	EUT PoE Port to Camera3 PoE Port	10M	Non-shielded, Detachable	RJ-45, with Plastic Head
LCD Monitor Data Cable	LCD Monitor DVI Port to EUT DVI Port	1.88M	Non-Shielded, Detachable	Metal Head
LCD Monitor Data Cable	LCD Monitor D-Sub Port to EUT D-Sub Port	1.88M	Non-Shielded, Detachable	Metal Head
Modem Data Cable*4	Modem to EUT COM port	1.5M	Shielded, Detachable	Metal Head
Keyboard Data Cable	Keyboard to PC PS2 port	1.8M	Shielded, Un-detachable	Metal Head



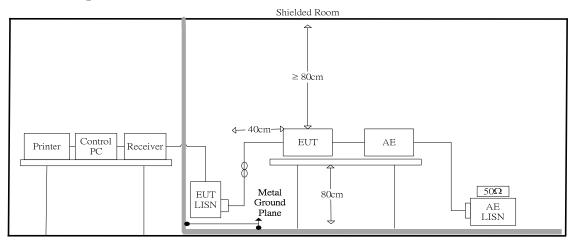
Description	Path	Cable Length	Cable Type	Connector Type
Mouse Data Cable	Mouse to PC PS2 port	1.8M	Shielded, Un-detachable	Metal Head
Microphone& Audio Data Cable*2	Microphone to EUT Microphone Port	1.9M	Non-shielded, Un-detachable	Plastic Head
Printer Data Cable	EUT Parallel port with Dummy	1.5M	Shielded, Detachable	Metal Head



# 2. Power Main Port Conducted Emissions

#### 2.1 Test Setup and Procedure

#### **2.1.1 Test Setup**



#### 2.1.2 Test Procedure

The measurements are performed in a  $3.5 \text{m} \times 3.4 \text{m} \times 2.5 \text{m}$  shielded room, which referred as Conduction 01 test site, or a  $3 \text{m} \times 3 \text{m} \times 2.3 \text{m}$  test site, which referred as Conduction 02 test site. The EUT was placed on non-conduction  $1.0 \text{m} \times 1.5 \text{m}$  table, which is 0.8 meters above an earth-grounded.

Power to the EUT was provided through the LISN which has the Impedance (50ohm/50uH) vs. Frequency Characteristic in accordance with the standard. Power to the LISNs were filtered to eliminate ambient signal interference and these filters were bonded to the ground plane. Peripheral equipment required to provide a functional system (support equipment) for EUT testing was powered from the second LISN through a ganged, metal power outlet box which is bonded to the ground plane at the LISN.

The interconnecting cables were arranged and moved to get the maximum measurement. Both the line of power cord, hot and neutral, were measured.

The highest emissions were analyzed in details by operating the spectrum analyzer in fixed tuned mode to determine the nature of the emissions and to provide information which could be useful in reducing their amplitude.

**Report Number: ISL-12HE051CE** 

#### 2.1.3 EMI Receiver/Spectrum Analyzer Configuration (for the frequencies tested)

Frequency Range: 150KHz--30MHz

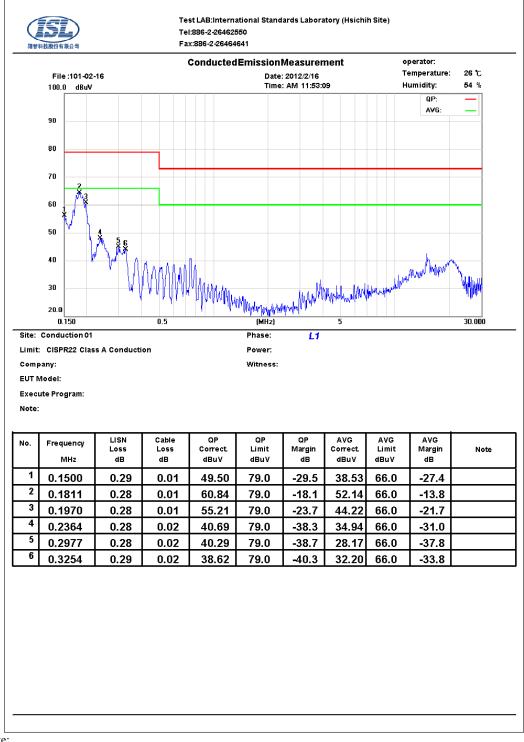
Detector Function: Quasi-Peak / Average Mode

Resolution Bandwidth: 9KHz



# 2.2 Conduction Test Data: Configuration 1

#### **Table 3.2.1 Power Line Conducted Emissions (Hot)**



Note:

Margin = Corrected Amplitude - Limit

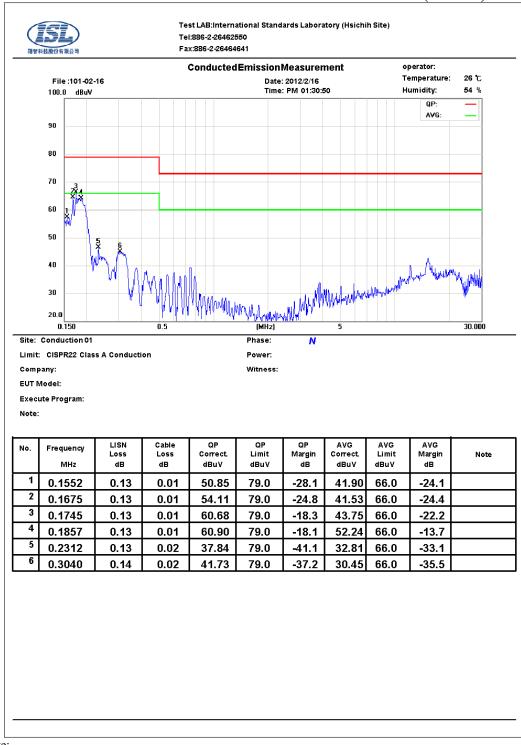
Corrected Amplitude = Receiver Reading + LISN Loss + Cable Loss

A margin of -8dB means that the emission is 8dB below the limit

The frequency spectrum graph is for final peak graph, and the attached table is for QP/AVG test result. If peak data can pass, it will be shown in "QP/AVG Correct" column, if not, QP/AVG data will instead.







Note:

Margin = Corrected Amplitude - Limit

 $Corrected\ Amplitude = Receiver\ Reading + LISN\ Loss + Cable\ Loss$ 

A margin of -8dB means that the emission is 8dB below the limit

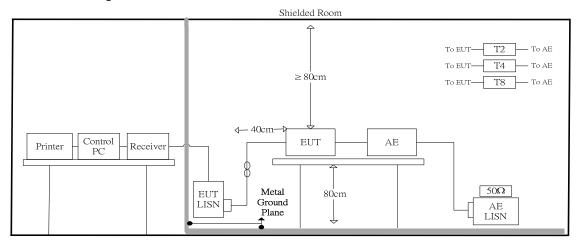
The frequency spectrum graph is for final peak graph, and the attached table is for QP/AVG test result. If peak data can pass, it will be shown in "QP/AVG Correct" column, if not, QP/AVG data will instead.



# 3. Telecommunication Port Conducted Emissions

#### 3.1 Test Setup and Procedure

#### 3.1.1 Test Setup



# 3.1.2 Test Procedure

The measurements are performed in a  $3.5 \text{m} \times 3.4 \text{m} \times 2.5 \text{m}$  shielded room, which referred as Conduction 01 test site, or a  $3 \text{m} \times 3 \text{m} \times 2.3 \text{m}$  test site, which referred as Conduction 02 test site. The EUT was placed on non-conduction  $1.0 \text{m} \times 1.5 \text{m}$  table, which is 0.8 meters above an earth-grounded.

The EUT, any support equipment, and any interconnecting cables were arranged and moved to get the maximum measurement.

Power to the EUT was provided through the LISN which has the Impedance (50 Ohm/50uH) vs. Frequency Characteristic in accordance with the standard. Power to the LISN was filtered to eliminate ambient signal interference and this filter was bonded to ground. Peripheral equipment to provide a functional system (support equipment) for EUT testing was powered through a ganged, metal power outlet box bonded to the ground. AC input power for the auxiliary power outlets was obtained from the same filtered source that provides input power to the LISN.

The highest emissions were analyzed in details by operating the spectrum analyzer in fixed tuned mode to determine the nature of the emissions and to provide information could be useful in reducing their amplitude.

**Report Number: ISL-12HE051CE** 

#### 3.1.3 EMI Receiver/Spectrum Analyzer Configuration (for the frequencies tested)

Frequency Range: 150KHz--30MHz

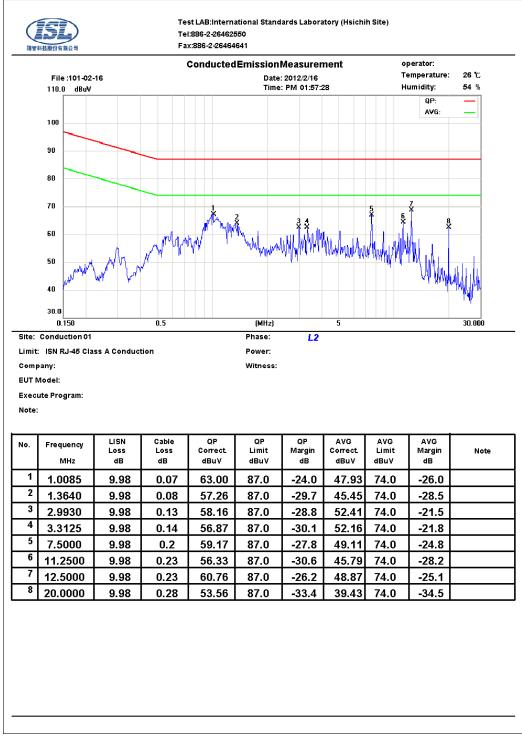
Detector Function: Quasi-Peak / Average Mode

Resolution Bandwidth: 9KHz



#### 3.2 Test Data: LAN--10M

**Table 4.2.1 Telecommunication Port Conducted Emission** 



#### Note:

 $Margin = Corrected\ Amplitude\ -\ Limit$ 

Corrected Amplitude = Receiver Reading + LISN Loss + Cable Loss

A margin of -8dB means that the emission is 8dB below the limit

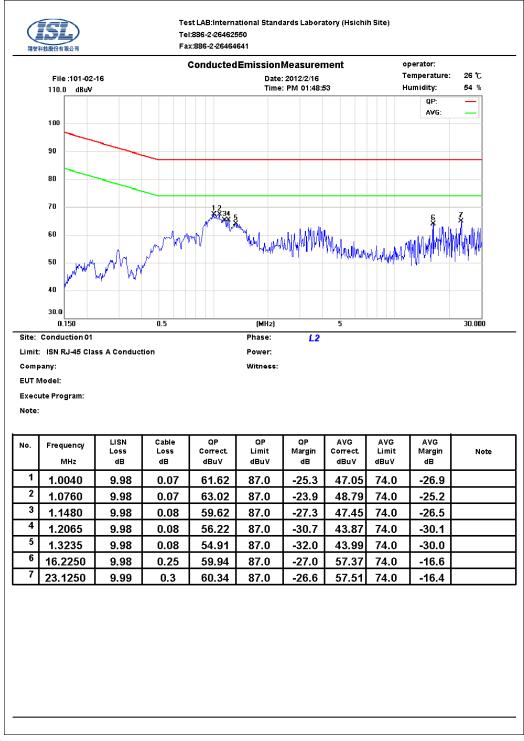
The frequency spectrum graph is for final peak graph, and the attached table is for QP/AVG test result.

If peak data can pass, it will be shown in "QP/AVG Correct" column, if not, QP/AVG data will instead.



#### 3.3 Test Data: LAN--100M

**Table 4.3.1 Telecommunication Port Conducted Emission** 



#### Note:

 $Margin = Corrected\ Amplitude\ -\ Limit$ 

Corrected Amplitude = Receiver Reading + LISN Loss + Cable Loss

A margin of -8dB means that the emission is 8dB below the limit

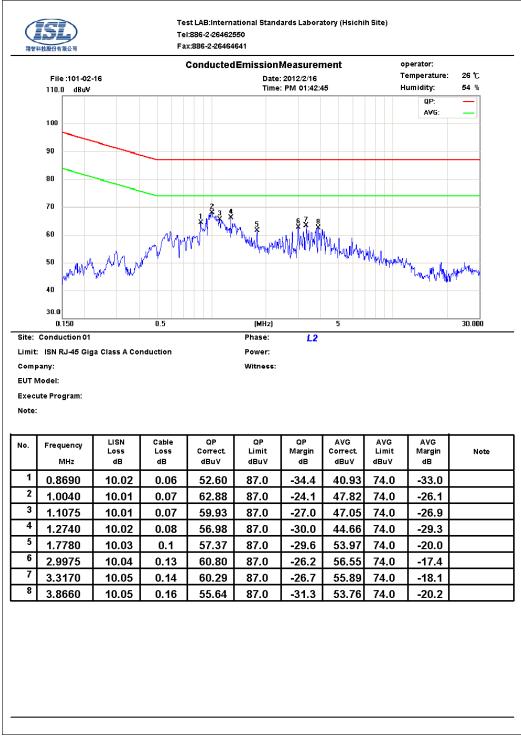
The frequency spectrum graph is for final peak graph, and the attached table is for QP/AVG test result.

If peak data can pass, it will be shown in "QP/AVG Correct" column, if not, QP/AVG data will instead.



#### 3.4 Test Data: LAN--GIGA

**Table 4.4.1 Telecommunication Port Conducted Emission** 



#### Note:

 $Margin = Corrected\ Amplitude\ -\ Limit$ 

 $Corrected\ Amplitude = Receiver\ Reading + LISN\ Loss + Cable\ Loss$ 

A margin of -8dB means that the emission is 8dB below the limit

The frequency spectrum graph is for final peak graph, and the attached table is for QP/AVG test result.

If peak data can pass, it will be shown in "QP/AVG Correct" column, if not, QP/AVG data will instead.



# 3.5 Test Data: LAN--100 (PoE)

#### **Table 4.5.1 Telecommunication Port Conducted Emission**



Address:No.120,Lane 180,San Ho Tsuen,Hsin Ho Road,Lung-Tan Hsiang, Tao Yuan Conty,Taiwan R.O.C. Tel:03-4071718

File :1 100.0 dBvV		Cond		on Measure ate: 2012/2/24 ime: AM 11:2	ı	t	operator: Temperatu Humidity:	re: 26 °C 54 %
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ва								
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Site: Conduction 02

Phase:

Witness:

Limit: ISN RJ-45 Class A Conduction

Power:

Company:

EUT Model: Execute Program:

Note:

No.	Frequency MHz	LISN Loss dB	Cable Loss dB	QP Correct. dBuV	QP Limit dBuV	QP Margin dB	AVG Correct. dBuV	AVG Limit dBuV	AVG Margin dB	Note
1	0.2100	10.09	0.01	67.51	94.21	-26.7	66.37	81.21	-14.8	
2	0.3140	10.08	0.02	69.79	90.86	-21.0	68.98	77.86	-8.88	
3	0.5220	10.07	0.03	64.35	87.00	-22.6	61.99	74.00	-12.0	
4	0.5980	10.06	0.03	67.56	87.00	-19.4	66.63	74.00	-7.37	
5	0.8940	10.04	0.04	60.71	87.00	-26.2	57.27	74.00	-16.7	
6	1.5620	10	0.07	55.58	87.00	-31.4	52.78	74.00	-21.2	

Note:

 $Margin = Corrected\ Amplitude\ -\ Limit$ 

 $Corrected\ Amplitude = Receiver\ Reading + LISN\ Loss + Cable\ Loss$ 

A margin of -8dB means that the emission is 8dB below the limit

The frequency spectrum graph is for final peak graph, and the attached table is for QP/AVG test result.

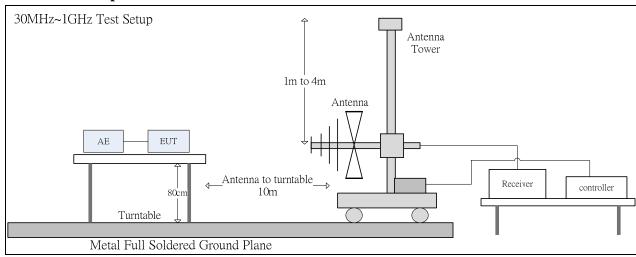
If peak data can pass, it will be shown in "QP/AVG Correct" column, if not, QP/AVG data will instead.

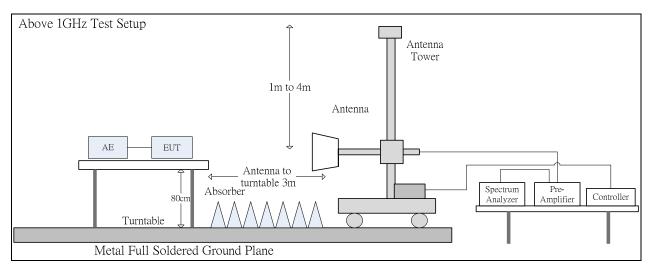


# 4. Radiated Disturbance Emissions

#### 4.1 Test Setup and Procedure

#### 4.1.1 Test Setup





#### 4.1.2 Test Procedure

The radiated emissions test will then be repeated on the open site or chamber to measure the amplitudes accurately and without the multiple reflections existing in the shielded room. The EUT and support equipment are set up on the turntable of one of 10 meter open field sites or 10 meter chamber. Desktop EUT are set up on a wooden stand 0.8 meter above the ground or floor-standing arrangement shall be placed on the horizontal ground reference plane. The test volume for a height of up to 30 cm may be obstructed by absorber placed on the ground plane.

For the initial measurements, the receiving antenna is varied from 1-4 meter height and is changed in the vertical plane from vertical to horizontal polarization at each frequency. The highest emissions between 30 MHz to 1000 MHz were analyzed in details by operating the spectrum analyzer and/or EMI receiver in quasi-peak mode to determine the precise amplitude of the emissions. The highest emissions between 1 GHz to 6 GHz were analyzed in details by operating the spectrum analyzer in peak and average mode to determine the precise amplitude of the emissions.



**Report Number: ISL-12HE051CE** 

At the highest amplitudes observed, the EUT is rotated in the horizontal plane while changing the antenna polarization in the vertical plane to maximize the reading. The interconnecting cables were arranged and moved to get the maximum measurement. Once the maximum reading is obtained, the antenna elevation and polarization will be varied between specified limits to maximize the readings.

The highest internal source of an EUT is defined as the highest frequency generated or used within the EUT or on which the EUT operates or tunes. If the highest frequency of the internal sources of the EUT is less than 108 MHz, the measurement shall only be made up to 1 GHz. If the highest frequency of the internal sources of the EUT is between 108 MHz and 500 MHz, the measurement shall only be made up to 2 GHz. If the highest frequency of the internal sources of the EUT is between 500 MHz and 1 GHz, the measurement shall only be made up to 5 GHz. If the highest frequency of the internal sources of the EUT is above 1 GHz, the measurement shall be made up to 5 times the highest frequency or 6 GHz, whichever is less.

# **4.1.3** Spectrum Analyzer Configuration (for the frequencies tested)

Frequency Range: 30MHz--1000MHz Detector Function: Quasi-Peak Mode

Resolution Bandwidth: 120KHz

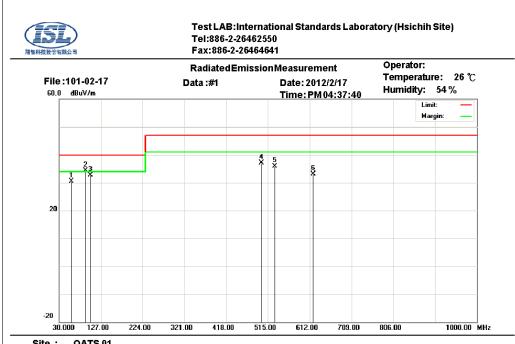
Frequency Range: Above 1 GHz to 6 GHz Detector Function: Peak/Average Mode

Resolution Bandwidth: 1MHz



# 4.2 Radiation Test Data: Configuration 1

# **Table 5.2.1 Radiated Emissions (Horizontal)**



OATS 01

Condition: CISPR22 ClassA 10M Radiation

Horizontal Polarization: Power:

**Report Number: ISL-12HE051CE** 

Company: **EUT Model:** Witness:

Execute Program:

Note:

No.	Frequency (MHz)	RX_R (dBuV/m)	Ant_F (dB)	Cab_L (dB)	PreAmp (dB)	Emission (dBuV/m)	Limit (dBuV/m)	Margin (dB)	Ant.Pos (cm)	Tab.Pos (deg.)	Detector
1	58.6400	21.73	7.89	0.84	0	30.46	40.00	-9.54	140	356	QP
2	90.9300	25.15	8.15	1	0	34.30	40.00	-5.70	139	333	QP
3	102.6600	20.31	11.26	1.05	0	32.62	40.00	-7.38	126	312	QP
4	499.1800	17.10	17.88	2.22	0	37.20	47.00	-9.80	226	205	QP
5	530.2800	15.44	18.14	2.3	0	35.88	47.00	-11.12	279	108	QP
6	618.9500	11.53	19.02	2.51	0	33.06	47.00	-13.94	375	162	QP

Margin = Corrected Amplitude – Limit

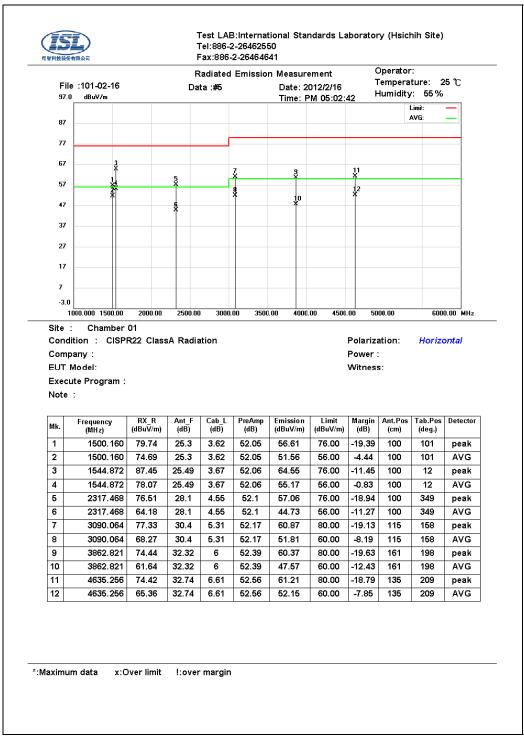
Corrected Amplitude = Radiated Amplitude + Antenna Correction Factor + Cable Loss – Pre-Amplifier Gain

A margin of -8dB means that the emission is 8dB below the limit

BILOG Antenna Distance: 10 meters

Below 1GHz test, if the peak measured value meets the QP limit, it is unnecessary to perform the QP measurement. measurement.





\* Note:

Margin = Corrected Amplitude – Limit

Corrected Amplitude = Radiated Amplitude + Antenna Correction Factor + Cable Loss - Pre-Amplifier Gain

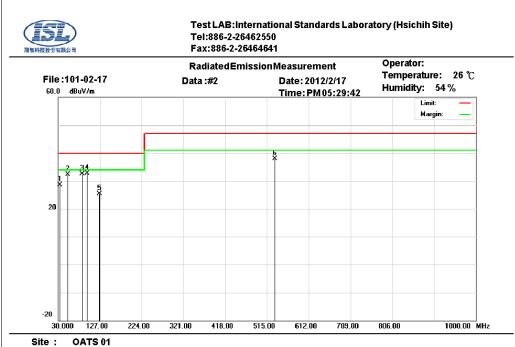
A margin of -8dB means that the emission is 8dB below the limit

Horn Antenna Distance: 3 meters

Above 1GHz test, if the peak measured value meets the average limit, it is unnecessary to perform the average measurement.



# **Table 5.2.2 Radiated Emissions (Vertical)**



Condition: CISPR22 ClassA 10M Radiation

Vertical Polarization: Power:

**Report Number: ISL-12HE051CE** 

Witness:

Company: EUT Model:

Execute Program:

Note:

No.	Frequency (MHz)	RX_R (dBuV/m)	Ant_F (dB)	Cab_L (dB)	PreAmp (dB)	Emission (dBuV/m)	Limit (dBuV/m)	Margin (dB)	Ant.Pos (cm)	Tab.Pos (deg.)	Detector
1	33.4600	9.28	18.61	0.67	0	28.56	40.00	-11.44	190	337	QP
2	52.1900	23.62	7.82	0.8	0	32.24	40.00	-7.76	178	137	QP
3	85.9500	23.76	7.78	0.98	0	32.52	40.00	-7.48	179	180	QP
4	97.1100	21.85	9.82	1.03	0	32.70	40.00	-7.30	130	292	QP
5	125.9000	10.14	13.98	1.16	0	25.28	40.00	-14.72	115	160	QP
6	532.6100	17.46	18.16	2.3	0	37.92	47.00	-9.08	107	343	QP

\* Note:

Margin = Corrected Amplitude - Limit

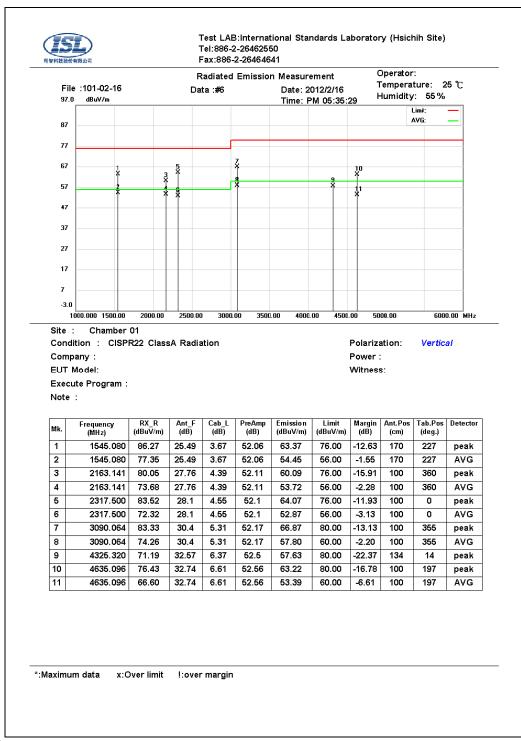
Corrected Amplitude = Radiated Amplitude + Antenna Correction Factor + Cable Loss – Pre-Amplifier Gain

A margin of -8dB means that the emission is 8dB below the limit

Distance: 10 meters BILOG Antenna

Below 1GHz test, if the peak measured value meets the QP limit, it is unnecessary to perform the QP measurement. measurement.





\* Note:

 $Margin = Corrected\ Amplitude - Limit$ 

Corrected Amplitude = Radiated Amplitude + Antenna Correction Factor + Cable Loss - Pre-Amplifier Gain

A margin of -8dB means that the emission is 8dB below the limit

Horn Antenna Distance: 3 meters

Above 1GHz test, if the peak measured value meets the average limit, it is unnecessary to perform the average measurement.



# 5. Electrostatic discharge (ESD) immunity

#### **5.1 Test Specification**

Port:	Enclosure			
Basic Standard:	EN 61000-4-2/ IEC EN61000-4-2			
	(details referred to Sec 1.2)			
Test Level:	Air +/- 2 kV, +/- 4 kV, +/- 8 kV			
	Contact +/- 4 kV			
Criteria:	В			
Test Procedure	refer to ISL QA -T4-E-S7			
Temperature:	25 °C			
Humidity:	56%			

# **Selected Test Point**

Air: discharges were applied to slots, aperture or insulating surfaces. 10 single air

discharges were applied to each selected points.

Contact: Total 200 discharges minimum were to the selected contact points.

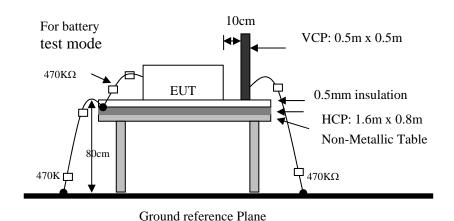
Indirect Contact Points: 25 discharges were applied to center of one edge of VCP and each EUT side of HCP with 10 cm away from EUT.

Red arrow lines indicate the contact points, and blue arrow lines indicate the air points.

# 5.2 Test Setup

EUT is 1m from the wall and other metallic structure. When Battery test mode is needed, a cable with one  $470 \text{K}\Omega$  resister at two rare ends is connected from metallic part of EUT and screwed to HCP.

**Report Number: ISL-12HE051CE** 

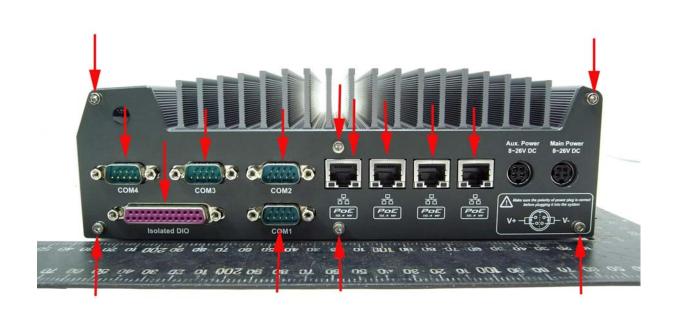


#### 5.3 Test Result

Performance of EUT complies with the given specification.



# **Test Data**







# 6. Radio-Frequency, Electromagnetic Field immunity

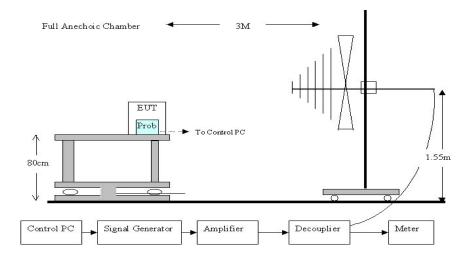
# **6.1 Test Specification**

Port:	Enclosure
Basic Standard:	EN 61000-4-3/ IEC EN61000-4-3
	(details referred to Sec 1.2)
Test Level:	3 V/m
Modulation:	AM 1KHz 80%
Frequency range:	80 MHz~1 GHz
Frequency Step:	1% of last step frequency
Dwell time:	3s
Polarization:	Vertical and Horizontal
EUT Azimuth Angle	⊠0° ⊠90° ⊠180° ⊠270°
Criteria:	A
Test Procedure	refer to ISL QA -T4-E-S8
Temperature:	24°C
Humidity:	67%

# 6.2 Test Setup

The field sensor is placed at one calibration grid point to check the intensity of the established fields on both polarizations. EUT is adjusted to have each side of EUT face coincident with the calibration plane. A CCD camera and speakers are used to monitor the condition of EUT for the performance judgment.

**Report Number: ISL-12HE051CE** 



# 6.3 Test Result

Performance of EUT complies with the given specification.



# 7. Electrical Fast transients/burst immunity

# 7.1 Test Specification

Port:	AC mains; Twisted Pair LAN Port
Basic Standard:	EN 61000-4-4/ IEC EN61000-4-4
	(details referred to Sec 1.2)
Test Level:	AC Power Port: +/- 1 kV
	Twisted Pair LAN Port (I/O Cables):
	+/- 0.5 kV
Rise Time:	5ns
Hold Time:	50ns
Repetition Frequency:	5KHz
Criteria:	В
Test Procedure	refer to ISL QA -T4-E-S9
Temperature:	25 °C
Humidity:	56%

# **Test Procedure**

The EUT was setup on a nonconductive table 0.1 m above a reference ground plane.

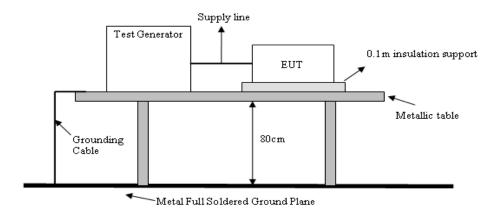
<b>Test Points</b>	Polarity	Result	Comment
Line	+	N	60 sec
	1	N	60 sec
Neutral	+	N	60 sec
	-	N	60 sec
Ground	+	N	60 sec
	-	N	60 sec
Line to	+	N	60 sec
Neutral	-	N	60 sec
Line to	+	N	60 sec
Ground	-	N	60 sec
Neutral to	+	N	60 sec
Ground	-	N	60 sec
Line to Neutral	+	N	60 sec
to Ground	-	N	60 sec
Capacitive coupling	+	N	60 sec
clamp	-	N	60 sec

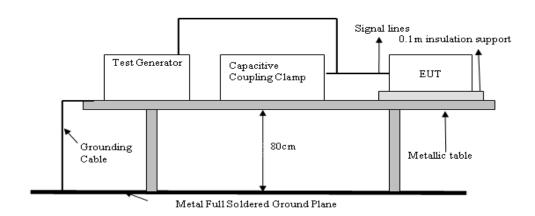
Note: 'N' means normal, the EUT function is correct during the test.



# 7.2 Test Setup

EUT is at least 50cm from the conductive structure.





# 7.3 Test Result

Performance of EUT complies with the given specification.



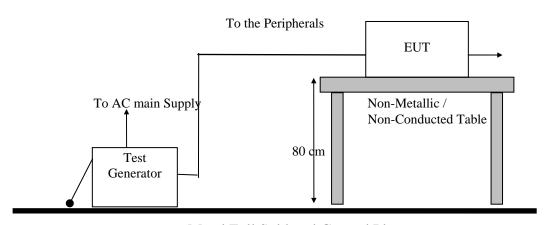
## 8. Surge Immunity

#### 8.1 Test Specification

Port:	AC mains
Basic Standard:	EN 61000-4-5/ IEC EN61000-4-5
	(details referred to Sec 1.2)
Test Level:	AC Power Port:
	Line to Line: +/- 0.5 kV, +/- 1 kV
	Line to Earth: +/- 0.5 kV, +/- 1 kV, +/- 2kV
Rise Time:	1.2us
Hold Time:	50us
Repetition Rate:	30 second
Angle:	⊠0° ⊠90° ⊠180° ⊠270°
Criteria:	В
Test Procedure	refer to ISL QA -T4-E-S10
Temperature:	25°C
Humidity:	56%

#### 8.2 Test Setup

AC power supply and Voltage Supply to EUT



Metal Full Soldered Ground Plane

**Report Number: ISL-12HE051CE** 

#### 8.3 Test Result

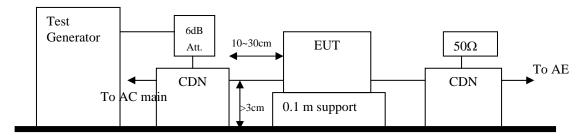


## 9. Immunity to Conductive Disturbance

#### 9.1 Test Specification

Port:	AC mains; Twisted Pair LAN Port
Basic Standard:	EN 61000-4-6/ IEC EN61000-4-6
	(details referred to Sec 1.2)
Test Level:	3 V
Modulation:	AM 1KHz 80%
Frequency range:	0.15 MHz - 80MHz
Frequency Step:	1% of last Frequency
Dwell time:	3s
Criteria:	A
CDN Type:	CDN M2+M3, CDN T2, CDN T4, CDN
	T8, EM Clamp
Test Procedure	refer to ISL QA -T4-E-S11
Temperature:	25°C
Humidity:	56%

#### 9.2 Test Setup



**Report Number: ISL-12HE051CE** 

Reference Ground Plane

#### 9.3 Test Result

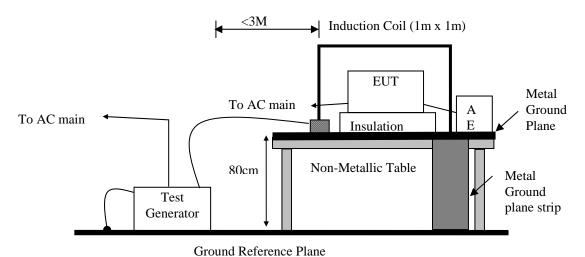


## 10. Power Frequency Magnetic Field immunity

#### 10.1 Test Specification

Port:	Enclosure
Basic Standard:	EN 61000-4-8/ IEC EN61000-4-8
	(details referred to Sec 1.2)
Test Level:	1A/m
Polarization:	X, Y, Z
Criteria:	A
Test Procedure	refer to ISL QA -T4-E-S12
Temperature:	25°C
Humidity:	56%

## 10.2 Test Setup



**Report Number: ISL-12HE051CE** 

#### 10.3 Test Result

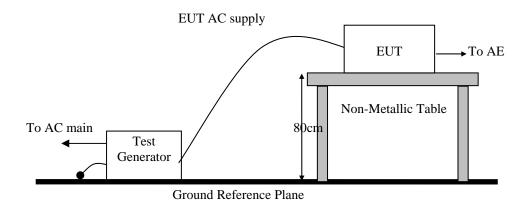


# 11. Voltage Dips, Short Interruption and Voltage Variation immunity

#### 11.1 Test Specification

Port:	AC mains
Basic Standard:	EN 61000-4-11/ IEC EN61000-4-11
	(details referred to Sec 1.2)
Test Level:	>95% in 0.5 period
Criteria:	В
Test Level:	30% in 25 period
Criteria:	C
Test Level:	>95% in 250 period
Criteria:	C
Phase:	0°; 180°
Test intervals:	3 times with 10s each
Test Procedure	refer to ISL QA -T4-E-S13
Temperature:	25°C
Humidity:	56%

#### 11.2 Test Setup



**Report Number: ISL-12HE051CE** 

#### 11.3 Test Result



#### 12. Harmonics

#### **12.1 Test Specification**

Port:	AC mains
Active Input Power:	>75W
Basic Standard:	EN61000-3-2/IEC 61000-3-2
	(details referred to Sec 1.2)
Test Duration:	2.5min
Class:	D
Test Procedure	refer to ISL QA -T4-E-S14
Temperature:	25°C
Humidity:	68%

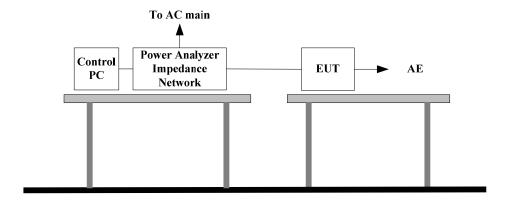
#### **Test Procedure**

The EUT is supplied in series with shunts or current transformers from a source having the same nominal voltage and frequency as the rated supply voltage and frequency of the EUT. The EUT is configured to its rated current with additional resistive load when the testing is performed.

Equipment having more than one rated voltage shall be tested at the rated voltage producing the highest harmonics as compared with the limits.

**Report Number: ISL-12HE051CE** 

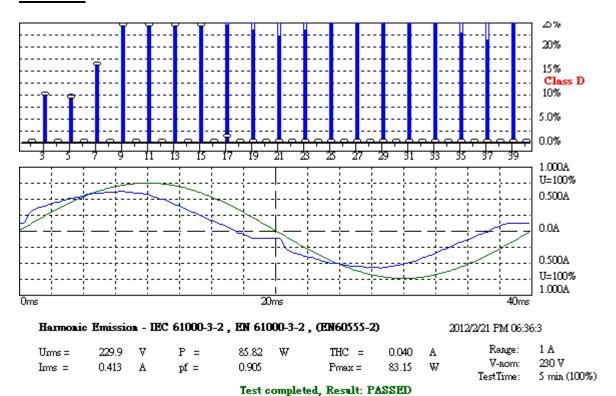
#### 12.2 Test Setup



#### 12.3 Test Result



#### **Test Data**



HAR-1000 PMC-Partner

**Report Number: ISL-12HE051CE** 

 $THDi = 10.2 \% \quad THDu = 0.10 \% \quad Class D$ 

Test - Time : 5min (100 %)

Limit Reference: Pmax = 83.149W

Test completed, Result: PASSED

Order	Freq.	Iavg	Iavg%L	Irms	Irms%L	Imax	Imax%L	Limit	Status
	[Hz]	[A]	[%]	[A]	[%]	[A]	[%]	[A]	
1	50	0.3819		0.3928		0.3990			
2	100	0.0000		0.0031		0.0045			
3	150	0.0278	9.8261	0.0281	9.9312	0.0281	9.9312	0.2827	
4	200	0.0000		0.0004		0.0005			
5	250	0.0145	9.2040	0.0143	9.0403	0.0155	9.8130	0.1580	
6	300	0.0000		0.0003		0.0004			
7	350	0.0133	16.047	0.0132	15.929	0.0137	16.443	0.0831	
8	400	0.0000		0.0004		0.0005			
9	450	0.0111	26.605	0.0111	26.719	0.0114	27.306	0.0416	
10	500	0.0000		0.0005		0.0005			

					24			(ISL)
					-34-			翔智科技股份有限公 International Standards Laborato
11	550	0.0091	31.279	0.0092	31.669	0.0095	32.717	0.0291
12	600	0.0000		0.0004		0.0005		
13	650	0.0070	28.494	0.0071	28.752	0.0071	29.000	0.0246
14	700	0.0000		0.0004		0.0004		
15	750	0.0054	25.496	0.0055	25.739	0.0058	27.169	0.0213
16	800	0.0000		0.0004		0.0005		
17	850	0.0002	1.0986	0.0046	24.309	0.0051	26.902	0.0188
18	900	0.0000		0.0005		0.0007		
19	950	0.0000	0.0000	0.0039	23.184	0.0043	25.720	0.0168
20	1000	0.0000		0.0006		0.0006		
21	1050	0.0000	0.0000	0.0034	22.021	0.0040	26.426	0.0152
22	1100	0.0000		0.0004		0.0005		
23	1150	0.0000	0.0000	0.0032	23.242	0.0043	31.135	0.0139
24	1200	0.0000		0.0004		0.0005		
25	1250	0.0000	0.0000	0.0032	25.263	0.0037	29.076	0.0128
26	1300	0.0000		0.0006		0.0008		
27	1350	0.0000	0.0000	0.0031	26.254	0.0037	31.402	0.0119
28	1400	0.0000		0.0008		0.0009		
29	1450	0.0000	0.0000	0.0034	30.963	0.0035	31.516	0.0110
30	1500	0.0000		0.0009		0.0010		
31	1550	0.0000	0.0000	0.0033	31.917	0.0039	37.827	0.0103
32	1600	0.0000		0.0008		0.0010		
33	1650	0.0000	0.0000	0.0026	27.055	0.0029	29.571	0.0097
34	1700	0.0000		0.0008		0.0009		
35	1750	0.0000	0.0000	0.0021	22.689	0.0024	26.025	0.0091
36	1800	0.0000		0.0006		0.0006		
37	1850	0.0000	0.0000	0.0018	21.163	0.0022	25.396	0.0087
38	1900	0.0000		0.0005		0.0005		

0.0000

0.0000

0.0000

0.0021

0.0004

25.282 0.0023

0.0004

1950

2000

39

40

28.256 0.0082



## 13. Voltage Fluctuations

#### **13.1** Test Specification

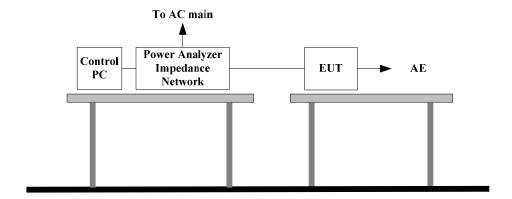
Port:	AC mains		
Basic Standard:	EN61000-3-3/IEC61000-3-3		
	(details referred to Sec 1.2)		
Test Procedure	refer to ISL QA -T4-E-S14		
Observation period:	For Pst 10min		
	For Plt 2 hours		
Temperature:	25°C		
Humidity:	68%		

#### **Test Procedure**

The EUT is supplied in series with reference impedance from a power source with the voltage and frequency as the nominal supply voltage and frequency of the EUT.

**Report Number: ISL-12HE051CE** 

#### 13.2 Test Setup

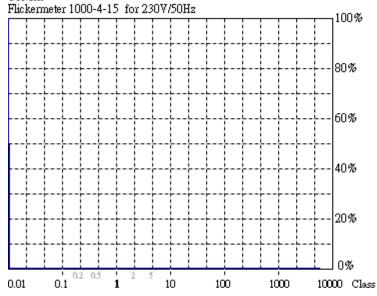


#### 13.3 Test Result



#### **Test Data**

10Min



Actual Flicker (Fli): 0.00

Short-term Flicker (Pst): 0.07

Limit (Pst): 1.00

Long-term Flicker (Plt): 0.07

Limit (Plt): 0.65

**Maximum Relative** 

**Volt. Change (dmax):** 0.00% Limit (dmax): 4.00%

D.1.4:... C4.................

Relative Steady-state
Voltage Change (dc): 0.03%
Limit (dc): 3.30%

Maximum Interval

exceeding 3.30% (dt): 0.00ms

Limit (dt>Lim): 500ms

Flicker Emission - IEC 61000-3-3, EN 61000-3-3, (EN60555-3)

Ums = 229.7 V P = 81.95 W Ims = 0.397 A pf = 0.899 2012/2/21 PM 04:00:3

Range: 1 A V-nom: 230 V

TestTime: 10 min (100%)

Test completed, Result: PASSED

HAR-1000 PMC-Partner

120Min

Actual Flicker (Fli): 0.00

Short-term Flicker (Pst): 0.07

Limit (Pst): 1.00

Long-term Flicker (Plt): 0.07 Limit (Plt): 0.65

Maximum Relative

**Volt. Change (dmax):** 0.00% Limit (dmax): 4.00%

Relative Steady-state

**Voltage Change (dc): 0.02%**Limit (dc): 3.30%

Maximum Interval

exceeding 3.30% (dt): 0.00ms

Limit (dt>Lim): 500ms

Flicker Emission - IEC 61000-3-3, EN 61000-3-3, (EN60555-3)

Ums = 229.7 V P = 76.72 W Ims = 0.376 A pf = 0.887 2012/2/21 PM 06:19:1

**Report Number: ISL-12HE051CE** 

Range: 1 A V-nom: 230 V

TestTime: 120 min (10000%)

Test completed, Result: PASSED

HAR-1000 PMC-Return



## 14. Appendix

## 14.1 Appendix A: Test Equipment

## 14.1.1 Test Equipment List

Location	<b>Equipment Name</b>	Brand	Model	S/N	Last Cal.	Next Cal.
CON01					Date	Date
Conduction	Coaxial Cable 1F-C1	EMEC	5D Cable	1F-C1	10/25/2011	10/25/2012
Conduction	LISN 02	EMCO	3825/2	1407	07/28/2011	07/28/2012
Conduction	LISN 03	R&S	ESH3-Z5	828874/010	07/28/2011	07/28/2012
			831.5518.52			
Conduction	ISN T2 03	FCC	FCC-TLISN-T	20618	07/28/2011	07/28/2012
			2-02			
Conduction	ISN T4 05	FCC	FCC-TLISN-T	20619	07/28/2011	07/28/2012
			4-02			
Conduction	ISN T8 03	FCC	FCC-TLINS-T	20620	07/28/2011	07/28/2012
			8-02			
Conduction	EMI Receiver 15	ROHDE &	ESCI	101166	04/19/2011	04/19/2012
		SCHWARZ				

Location	<b>Equipment Name</b>	Brand	Model	S/N	Last Cal.	Next Cal.
OATS01					Date	Date
Radiation	BILOG Antenna 10	Sumol	ЈВ1	A013004-1	07/18/2011	07/18/2012
		Sciences				
Radiation	Coaxial Cable 3F-10M	EMCI	CFD400-NL	ISL-R001	03/15/2011	03/15/2012
Radiation	EMI Receiver 13	ROHDE &	ESCI	101015	02/17/2011	02/17/2012
		SCHWARZ				

Location	<b>Equipment Name</b>	Brand	Model	S/N	Last Cal.	Next Cal.
Chamber 01					Date	Date
Rad. above	Horn Antenna 01	EMCO	3115	9504-4462	11/23/2011	11/23/2012
1Ghz						
Rad. above	Horn Antenna 03	COM-Power	AH-826	100A	03/15/2011	03/15/2013
1Ghz						
Rad. above	Microwave Cable-06	HUBER	SUCFLEX 106	60404/6	07/13/2011	07/13/2012
1Ghz		SUHNER				
Rad. above	Preamplifier 17	EMCI	EMC 01630	980009	08/03/2011	08/03/2012
1Ghz						
Rad. above	Preamplifier 20	EMCI	EMC051845	980084	10/26/2011	10/26/2012
1Ghz						
Rad. above	Spectrum Analyzer 23	ROHDE &	FSU43	101255	10/06/2011	10/06/2012
1Ghz		SCHWARZ				



Location	<b>Equipment Name</b>	Brand	Model	S/N	Last Cal. Date	Next Cal. Date
EN61K-3-2/3	DC Burn-In Load 02	D-RAM	DBS-2100	2100-910027	N/A	N/A
EN61K-3-2/3	Harmonic/Flicker Test	EMC Partner	HARMONICS	178	03/29/2011	03/29/2012
	System 03		-1000			
EN61K-4-,4,5,	TRANSIENT 2000 01	EMC Partner	TRANSIENT-	950	12/01/2011	12/01/2012
8,11			2000			
EN61K-4-2	ESD GUN 04	Schaffner	NSG 438	489	03/23/2011	03/23/2012
EN61K-4-3	BILOG Antenna 06	Schaffner	CBL6112B	2754	N/A	N/A
EN61K-4-3	Amplifier 80Mz~1GHz 250W	AR	250W1000A	312494	N/A	N/A
EN61K-4-3	Amplifier 800MHz~3.0GHz 60W	AR	60S1G3	312762	N/A	N/A
EN61K-4-3	Broadband coupler 10K~220Mhz	Amplifier Research	DC2500	19810	N/A	N/A
EN61K-4-3	Broadband Coupler 80M~1GHz	Amplifier Research	DC6180	20364	N/A	N/A
EN61K-4-3	Broadband Coupler 1~4GHz	Werlatone	C5291	6516	N/A	N/A
EN61K-4-3	Coaxial Cable Chmb 04-3M-2	Belden	RG-8/U	Chmb 04-3M-2	N/A	N/A
EN61K-4-3	Signal Generator 03	Anritsu	MG3642A	6200162550	06/10/2011	06/10/2012
EN61K-4-4	Digital Oscilloscope	Tektronix	TDS 684A	B010761	N/A	N/A
EN61K-4-4	EFT Clamp	Precision	1604242	CNEFT1000-1 03	N/A	N/A
EN61K-4-5	CDN-UTP8 01	EMC Partner	CDN-UTP8	032	12/01/2011	12/01/2012
EN61K-4-5	SURGE-TESTER 01	EMC Partner	MIG0603IN3	778	12/01/2011	12/01/2012
EN61K-4-6	6dB Attenuator	Weinschel Corp	33-6-34	BC5975	N/A	N/A
EN61K-4-6	Amplifier 4-6	Amplifier Research	150A100	1-1-R-02157	N/A	N/A
EN61K-4-6	Attenuator 6dB 4-6	BIRO	100-A-FFN-06	0123	N/A	N/A
EN61K-4-6	CDN M2+M3	Frankonia	M2+M3	A3011016	07/30/2011	07/30/2012
EN61K-4-6	CDN T2 01	Frankonia	T2	A3010003	07/30/2011	07/30/2012
EN61K-4-6	CDN T4 05	FCC Inc.	FCC-801-T4-R J45	08020	08/26/2011	08/26/2012
EN61K-4-6	CDN T8 01	FCC Inc.	FCC-801-T8-R J45	08021	08/26/2011	08/26/2012
EN61K-4-6	EM-Clamp 01	FCC	F-203I-23MM	539	N/A	N/A
EN61K-4-6	Coaxial Cable 4-6 01-1	Harbour Industries	M17/128-RG4 00		N/A	N/A
EN61K-4-6	Coaxial Cable 4-6 01-2	Harbour Industries	M17/128-RG4 00	4-6 01-2	N/A	N/A
EN61K-4-6	Coaxial Cable 4-6 01-3	Harbour Industries	M17/128-RG4 00	4-6 01-3	N/A	N/A
EN61K-4-6	KAL-AD RJ45S	BIRO			N/A	N/A
EN61K-4-6	KAL-AD T2	BIRO			N/A	N/A
EN61K-4-6	Passive Impedance Adaptor 4-6	FCC	FCC-801-150- 50-CDN	9758;9759	N/A	N/A
EN61K-4-6, CISPR 13,	Signal Generator 02	НР	8648B	3642U01040	08/18/2011	08/18/2012
Antenna	M	D	TD 417445	ME1000 22	NT / A	NT/A
EN61K-4-8	Magnetic Field Antenna	Precision	TRAIZ44B	MF1000-23	N/A	N/A

PS: N/A => The equipment does not need calibration.



#### 14.1.2 Software for Controlling Spectrum/Receiver and Calculating Test Data

Test Item	Filename	Version
EN61000-3-2	HARCS.EXE	4.16
EN61000-3-3	HARCS.EXE	4.16
EN61000-4-3	Tile.Exe	2.0.P
EN61000-4-6	EN61000-4-6 Application Software	1.13.e
EN61000-4-2	N/A	2.0
EN61000-4-4	Tema.EXE	1.69
EN61000-4-5	Tema.EXE	1.69
EN61000-4-8	N/A	
EN61000-4-11	VDS-2002Rs.EXE	2.00

Radiation/Conduction	Filename	Version	<b>Issued Date</b>
Hsichih Conduction	EZ EMC	1.1.4.2	2/10/2007
Hsichih Radiation	EZ EMC	1.1.4.2	1/24/2007



#### 14.2 Appendix B: Uncertainty of Measurement

The measurement uncertainty refers to CISPR 16-4-2:2003. The coverage factor k=2 yields approximately a 95 % level of confidence.

<Conduction 01>  $\pm 3.262$ dB

<OATS 01 (10M)>

Horizontal

30MHz~200MHz: ±4.216 dB 200MHz~1GHz: ±4.438 dB

Vertical

30MHz~200MHz: ±4.342 dB 200MHz~1GHz: ±4.426 dB

<Chamber 01 (3M)>

1GHz~18GHz:  $\pm$  3.515dB 18GHz~26.5GHz:  $\pm$  3.424dB



<Immunity 01>

Test item	Uncertainty	
EN61000-4-2 (ESD)		
Rise time tr	≦ 15%	
Peak current Ip	≦ 6.3%	
current at 30 ns	≤ 6.3%	
current at 60 ns	≦ 6.3%	
EN61000-4-3 (RS)	± 1.776dB	
EN61000-4-4 (EFT)		
Time	± 1.427%	
Voltage	± 1.110 %	
Current		
EN61000-4-5 (Surge)		
Time	± 0.588 %	
Voltage	± 1.282 %	
Current	± 1.282 %	
EN61000-4-6 (CS)	± 1.892dB	
CDN	± 1.36dB	
EM Clamp	± 3.19dB	
EN61000-4-8 (Magnetic)	± 1.728%	
EN61000-4-11 (Dips)		
Time	±1.159%	
Voltage	±0.100%	
Current	±1.177%	
EN61000-3-2 (Harmonics)	±1.879 %	
EN61000-3-3 (Fluctuations and Flicker)	±1.879 %	



#### 14.3 Appendix C: Photographs of EUT Configuration Test Set Up

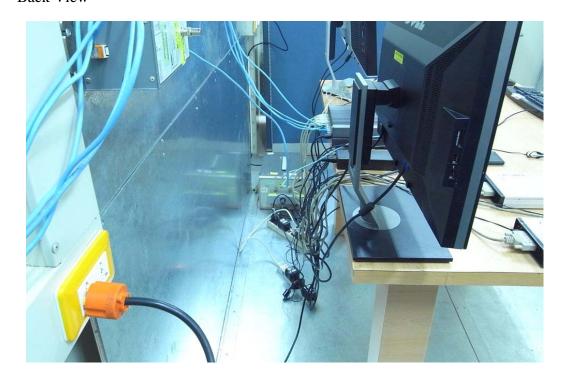
## 14.3.1 Photo of Main Power Port Conducted Emission and Telecommunication Port Conducted Emission Measurement

Front View













#### 14.3.2 Photo of Radiated Emission Measurement

Front View (30MHz~1GHz)



Back View (30MHz~1GHz)





#### 14.3.3 Photo of ESD Measurement



## 14.3.4 Photo of RF Field Strength Susceptibility Measurement





#### 14.3.5 Photo of Electrical Fast Transient/Burst Measurement



#### 14.3.6 Photo of Surge Measurement





#### 14.3.7 Photo of Conductive Measurement



## 14.3.8 Photo of Magnetic field Measurement





#### 14.3.9 Photo of Voltage Dips Measurement



## 14.3.10 Photo of Harmonics and Voltage Fluctuations





#### 14.4 Appendix D: Photographs of EUT

Please refer to the File of ISL-12HE051P